

Notice of References Cited	Application/Control No. 10/709,908	Applicant(s)/Patent Under Reexamination IDE, HIROYUKI	
	Examiner CHIA-WEI A. CHEN	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0156209	08-2003	YANAI, TOSHIKAZU	348/272
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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